

**CONVEX Diagnostics Master Index**  
**(C1, C120)**

Document No. 760-000930-000

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Third Edition  
December 1989

DA

**CONVEX Computer Corporation**  
Richardson, Texas USA

Sheet 1 of 1

CONVEX Diagnostics Master Index  
(C1, C120)

Description	Date	Document No.
This document contains a listing of all the diagnostic tests available for the CONVEX C1 and C120 computers.	1989	DHW-073
<p><b>CONVEX Diagnostics Master Index</b> (C1, C120)</p> <p>Order No. DHW-073</p> <p>Third Edition</p>		
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**Revision Sheet**  
**CONVEX Diagnostics Master Index**  
**(C1, C120)**

Edition	Document No.	Date	Description
Third	760-000930-000	December 1989	This edition reflects a new master index.
Second	760-000133-200	May 1989	This edition reflects a change in the name of the manual to <i>CONVEX Diagnostics Master Index (C1, C120)</i> . Also, the master table of contents has been eliminated.
First	760-000003-200	October 1988	Describes the four manuals comprising the kit. Provides a master table of contents and index to all manuals.

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# Chapter 1

## Introduction

### 1.1 Overview

*CONVEX Diagnostics Documentation (C1, C120)* contains four separate volumes of diagnostic materials. This manual introduces the structure of the *CONVEX Diagnostics Documentation (C1, C120)*. It also includes a master index to all four volumes.

The *CONVEX Diagnostics Documentation (C1, C120)* is a reference tool for CONVEX personnel who use the diagnostic utilities, CONVEX customers who do their own maintenance, and the CONVEX diagnostics sustaining staff.

### 1.2 Scope

This documentation applies to all CONVEX C1 and C120 computers.

### 1.3 Documents Included

This documentation kit includes the following four CONVEX manuals:

- **Volume I, *CONVEX Diagnostics Master Index (C1, C120)***—Use this manual to obtain a general overview of the diagnostics documentation and to find the master index to all diagnostic documentation
- **Volume II, *CONVEX Processor Diagnostics Manual (C1, C120)***—This reference manual documents the Service Processor Unit (SPU)-based processor diagnostics for the CONVEX C1 and C120 computers. Test programs for the SPU, main memory, and the Central Processor Unit (CPU) are described in this manual. Input/Output (I/O) and peripheral test programs are documented in *PBUS I/O System Diagnostics* manual.
- **Volume III, *CONVEX PBUS I/O System Diagnostics Manual***—This manual encompasses the operation and interpretation of the various Input/Output (I/O) system functional tests. These tests are system independent and will run on any CONVEX machine structure.
- **Volume IV, *CONVEX Diagnostic Utilities Manual (C1, C120)***—This document presents the diagnostic utilities for CONVEX C1 and C120 computers. The material describes the features of the Service Processor Unit (SPU) operating system and contains all diagnostic utilities for CONVEX C1 and C120 machines. This manual also contains a detailed explanation of the Diagnostics Shell (Dshell) and the scan utilities and diagnostic file formats.

## 1.4 Dependencies

All volumes in this kit are designed to be used together to eliminate excessive repetition of technical data between manuals and to simplify the revision process. The master table of contents and master index are comprehensive reference tools that make using the kit easier.

## 1.5 Master Index

The master index, in Chapter 3, makes finding a particular subject easier across all volumes.

### 1.5.1 Alphabetization

The index contains symbol and numeric sections as well as the usual alphabetical section. Alphabetization is in the following order:

1. symbols
2. numerals
3. letters from A to Z

### 1.5.2 Locators

#### NOTE

Due to variations in update releases, only the *Overview* manual in this kit has Roman numerals preceding the chapter-page numbers. However, in the master index, Roman numerals do precede locators to all manuals. This discrepancy will be corrected in the next release of each manual.

Refer to the "Documents Included" section for the Roman numerals assigned to each volume.

Each chapter-page number (which is the chapter number followed by a dash, then the page number of that chapter) is preceded by a Roman numeral that indicates the volume referenced. A period is placed between the volume number and the chapter-page number. The following is an example index entry:

TAC, reporting problems to, I.1-4, III.B-1, IV.xv, IV.A-1

The above entry indicates that references to "reporting problems to the TAC" appear on page 47 of Chapter 1 of the *CONVEX Diagnostics Documentation Overview (C1, C120)*, on page I of Appendix B of the *CONVEX PBUS I/O System Diagnostics Manual (C1, C120)*, and on page xv of the Preface and on page 1 of Appendix A of the *CONVEX Diagnostic Utilities Manual (C1, C120)*,

### 1.5.3 Cross-references

See cross-references guide the reader to preferred spellings and entry wording. See also cross-references point the way to related subjects.

## 1.6 Associated Documentation

The following is a partial list of other manuals or books that may provide more detailed information on the topics presented in this kit:

- *CONVEX SPU UNIX Utilities Manual*, Order No. DHW-007
- *CONVEX Processor Operation Guide (C100 Series, C200 Series)*, Order No. DHW-015
- *CONVEX Architecture Reference*, Order No. DHW-005
- *CONVEX UNIX Tutorial Papers*, Order No. DHW-002
- *The C Programming Language*, Kernighan & Ritchie, Order No. DSW-046

### 1.6.1 Ordering Documentation

To order the most current version of this or any other CONVEX document, use the CONVEX product number. If the product number is not known, order by the exact title. In some situations, the most current version may not be desired. To receive a specific version of a manual, order the manual by its document, or part, number, which can be obtained by contacting the local CONVEX office or by calling the Technical Assistance Center.

The product number for this manual is DHW-073.  
The document number for this manual is 760-000930-000.

#### 1.6.1.1 Diagnostic Documentation Kit

To order all four volumes of the *CONVEX Diagnostics Documentation (C1, C120)*:

The product number for the document set is DHW-070.  
The document number for the kit is 760-000022-200.

CONVEX documents can be ordered by mail by sending a request to:

CONVEX Computer Corporation  
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## Technical Assistance

Hardware and software support can be obtained through the CONVEX Technical Assistance Center (TAC):

- From all locations in the continental United States, call 1(800)952-0379.
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## Reader's Forum

If you wish to mail your comments to us, please use the form at the end of this manual and list the document page number with your questions and comments. Thank you.

# Acknowledgments

I would like to thank the following people for their contributions to this document:

- Technical contributors: Brian Allison, Tom Ford, Steve Gardner, Tony Jones, Joe Machado, Dave Rotheroe, Jeff Venters, Faron Wickey, Nathan Zelle
- Document review team: Art Clark, John Clark, Don Davis, Ron Engleking, Steve Fieler, Art Fischman, Dave Massey, Rick Miller, Craig Reed, Chip Stroup
- Hardware Documentation staff: Jimmie Holmes, Barbara Morris, Randall Stiles, Louis Talant

Without the efforts of all the aforementioned, this document would not have been possible.

Larry S. Bonura, Lead Writer  
CONVEX Hardware Documentation



Introduction  
Subsequent Pages

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# Chapter 2

## Master Index

### 2.1 Overview

This chapter contains the master index to the four volumes that comprise the *CONVEX Diagnostics Documentation* kit.

convex diagnostics

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